## Search Notes



## Application/Control No. Applicant(s)/Patent Under Reexamination DE LEIJ ET AL. Examiner Qian Ph.D., Celine X Applicant(s)/Patent Under Reexamination DE LEIJ ET AL.

SEARCHED					
Class	Subclass	Date	Examiner		

SEARCH NOTES					
Search Notes	Date	Examiner			
Search updated.	9/15/06	CQ			
Search updated	5/24/2007	CQ			
Search updated	10/23/2007	CQ			
Search updated	4/24/2008	CQ			

INTERFERENCE SEARCH					
Class	Subclass	Date	Examiner		
	Interference search performed by STIC in interference database(see score)	4/24/2008	CQ		

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